



## 17. TEST PHOTOGRAPHS

See following Attached Pages for setup photographs.

|   |   |                                       |   |  |
|---|---|---------------------------------------|---|--|
| <b>FCC ID:</b> A3LSMJ327P               |  | <b>HAC (RF EMISSIONS) TEST REPORT</b> |  | <b>Reviewed by:</b><br>Quality Manager |
| <b>Filename:</b><br>0Y1609221595-R1.A3L | <b>Test Dates:</b><br>10/03/2016 - 10/31/2016                                       | <b>DUT Type:</b><br>Portable Handset  |   | Page 62 of 64                          |

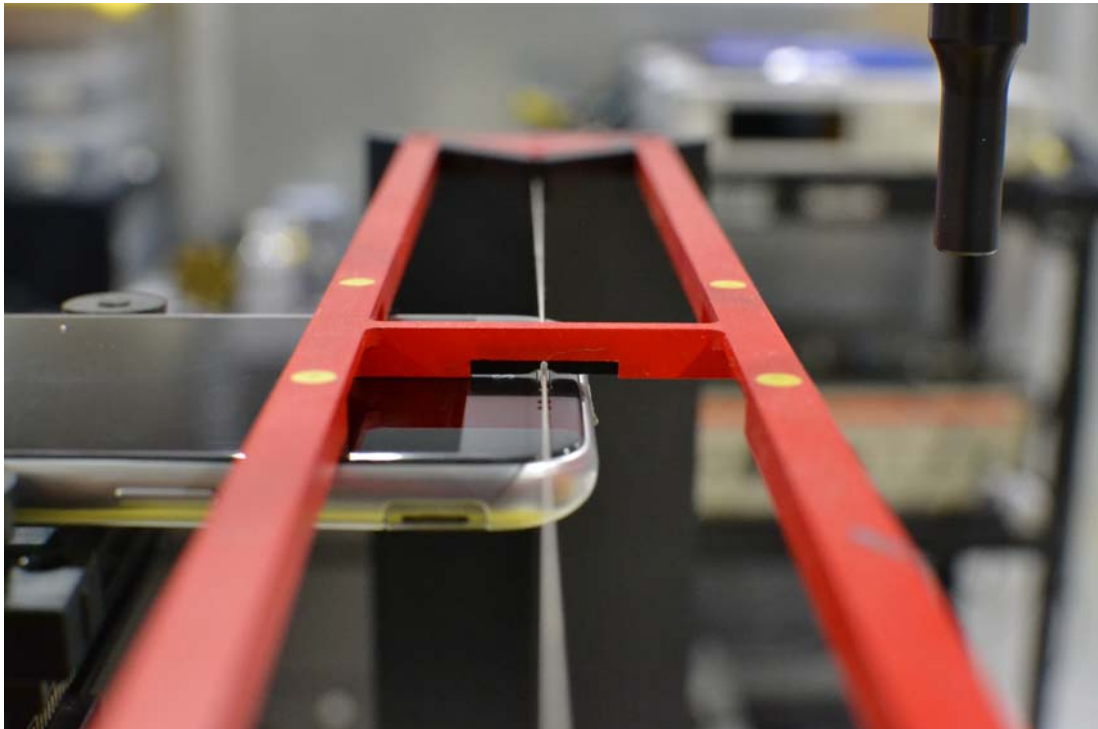
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09/07/2016



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**Figure 17-1**  
**Ear Reference Point HAC Phantom Alignment**



**Figure 17-2**  
**HAC Phantom Plane Alignment**

|   |   |                                       |   |  |
|---|---|---------------------------------------|---|--|
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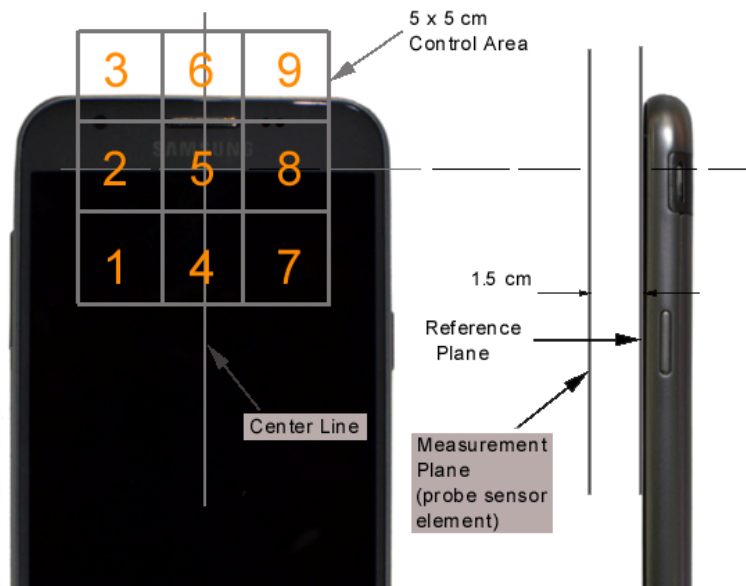




Figure 17-3 5x5 Scan grid above WD



Figure 17-4 E-Field WD Scan overlay

|                                  |   |                                |   |                                 |
|----------------------------------|---|--------------------------------|---|---------------------------------|
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